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# TABLE OF CONTENTS

<b>New High Temperature Ceramic Capacitor</b> .....	1
<i>Alan Devoe, Reginald L. Hofmaier, Linda Ngo</i>	
<b>Robust Class-I Dielectric for High Temperature Applications</b> .....	9
<i>Xilin Xu, Jim Magee, Adriana Hoskins, Mark Laps, Abhijit Gurav, Gai-Ying Yang, Clive Randall</i>	
<b>Film Capacitors for Automotive and Industrial Applications</b> .....	23
<i>Davide Montanari, Kimmo Saarinen, Fabio Scagliarini, Dietmar Zeidler, Matti Niskala, Claes Nender</i>	
<b>High Performance Polymer Film Dielectrics for Air Force Wide-Temperature Power Electronics Applications</b> .....	39
<i>Narayanan Venkat, Victor K. McNier, Bang-Hung Tsao, Thuy D. Dang, Jennifer N. Decerbo, Jeffery T. Stricker</i>	
<b>Further Electrolyte Development for High Temperature Aluminium Electrolytic Capacitors</b> .....	56
<i>Rong Xu, Alfonso Berduque, Zongli Dou</i>	
<b>A Charge-based Model for the Time Progression of Field Crystallization in Tantalum Pentoxide</b> .....	68
<i>Joachim Hossick-Schott</i>	
<b>Pulse De-rating and End of Life (EOL) for High Reliability Resistors</b> .....	76
<i>M. J. Cozzolino</i>	
<b>Low Capacitance ESD Protection Devices</b> .....	90
<i>Eran J. Jones</i>	
<b>Challenge: Highest Capacitance Tantalum Powders</b> .....	98
<i>Helmut Haas, Christoph Schnitter, Nobuyuki Sato, Hikmet Karabulut, Yohsuke Fujimori, Oliver Thomas</i>	
<b>Overview: Ultracapacitors and Ultracapacitor Applications</b> .....	110
<i>Michael A. Everett</i>	
<b>Electrochemical Capacitor Technology Basics for the Traditional Component Engineer</b> .....	143
<i>John R. Miller</i>	
<b>High CV Tantalum Capacitors - Challenges and Limitations</b> .....	159
<i>I. Horacek, T. Zednicek, S. Zednicek, T. Karnik, J. Petržilek, P. Jacisko, P. Gregorova, I. Pinwill</i>	
<b>Electrical Characterization of Polymer Tantalum Capacitors with Poly (3,4-ethylenedioxythiophene) Cathode</b> .....	175
<i>Yuri Freeman, William R. Harrell, Igor Luzinov, Brian Holman, Philip Lessner</i>	
<b>Broadband Antenna Design for Multi-band WiMax Applications</b> .....	185
<i>D. E. J. Humphrey, P. O'Riordan, D. Kearney</i>	
<b>Flexible Termination – Reliability in Stringent Environments</b> .....	195
<i>John Prymak, Corey Antoniadis, Peter Blais, Allen Hill, Ken Lai, Mark Laps, Kevin Lynn, Reggie Phillips, Cory Riedl, Axel Schmidt, Bill Sloka, Paul Staubli</i>	
<b>Characterizing the Effects of Inductor Coupling on the Performance of an Interleaved Boost Converter</b> .....	203
<i>Hiroyuki Kosai, Seana McNeal, Austin Page, Brett Jordan, Jim Scofield, Biswajit Ray</i>	
<b>DC/DC Converter Output Capacitor Benchmark</b> .....	218
<i>R. Faltus, Z. Flegr, R. Šponar, M. Jáne, T. Zednicek</i>	
<b>Small Case Size Polymer Now Comes in Ultra Low ESR</b> .....	230
<i>Antony Chacko, Jayson Young, Randy Hahn</i>	
<b>Characteristic Properties of Cellulose Materials Modified by Chitosan</b> .....	240
<i>A. Maslyakova, N. Zhuravleva</i>	
<b>How to Measure Low-ESL Tantalum Polymer Capacitors</b> .....	243
<i>Erik Reed</i>	
<b>Flaw Size Detectability In Barium Titanate Based Ceramic Capacitors Using Ultra High Frequency Acoustic Microscopy</b> .....	259
<i>Christine E. Pollock</i>	
<b>A Study Of Field Crystallization In Tantalum Capacitors And Its Effect On DCL And Reliability</b> .....	266
<i>T. Zednicek, J. Sikula, H. Leibovitz</i>	
<b>Effects of Copper Powder Shape on Sintering Behavior of Termination in MLCC</b> .....	282
<i>C. H. Kim, M. J. Park, B. J. Jeon, H. H. Gu, K. H. Lee, J. W. Uhm, Y. G. Kwon, Y. T. Kim, K. H. Hur</i>	
<b>Analysis on Discoloration of MLCC Dielectric in DPA</b> .....	289
<i>Peiyi Xiao, Zhigang Tan, Yongwei Deng</i>	
<b>Ta and NbO High Voltage Capacitors: Leakage Current Kinetics for MnO<sub>2</sub> and Conducting Polymer Cathode</b> .....	297
<i>J. Sikula, V. Sedlakova, H. Navarova, J. Majzner, M. Tacano, T. Zednicek</i>	

<b>Reliability of Embedded Planar Capacitors under Temperature and Voltage Stress</b> .....	307
<i>Mohammed A. Alam, Michael H. Azarian, Michael Osterman, Michael Pecht</i>	
<b>Classification of Non-IC Electronic Components for Assembly Processes - J-STD-075</b> .....	321
<i>Paul Krystek</i>	
<b>Novel Precipitation Method for Producing Dispersed Crystalline Copper Powders for Electronic Applications</b> .....	335
<i>Dan V. Goia, Ionel Halaciuga, Sulas Laplante</i>	
<b>Polymer Aluminum Electrolytic Capacitors with Chemically-Polymerized Polypyrrole (PPy) as Cathode Materials - Part I. Effect of Monomer Concentration and Oxidant on Electrical Properties of the Capacitors</b> .....	343
<i>Yining Kevin Zhang</i>	
<b>Electrical Properties of a Novel High CV Wet Tantalum Capacitor System</b> .....	355
<i>Douglas M. Edson, James S. Bates</i>	
<b>Production of Tantalum Powders Using the Cambridge FFC Reduction Method</b> .....	367
<i>Ian Margerison</i>	
<b>Challenges of Lead-Free Low Silver Content End Termination Pastes for Inductor Applications</b> .....	375
<i>Dong Zhang, Meg Tredinnick, Mark Challingsworth</i>	
<b>Author Index</b>	